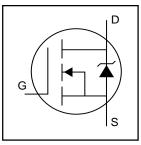
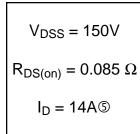
PD - 94390

IRLI3615

HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated

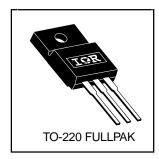




Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 Fullpak eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The Fullpak is mounted to a heatsink using a single clip or by a single screw fixing.



Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V	14 ⑤	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	9.8	Α
I _{DM}	Pulsed Drain Current ①	56	
P _D @T _C = 25°C	Power Dissipation	45	W
	Linear Derating Factor	0.30	W/°C
V_{GS}	Gate-to-Source Voltage	±16	V
E _{AS}	Single Pulse Avalanche Energy@	340	mJ
I _{AR}	Avalanche Current®	8.4	А
E _{AR}	Repetitive Avalanche Energy®	4.5	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units	
$R_{\theta JC}$	Junction-to-Case		3.3	°C/W	
$R_{\theta JA}$	Junction-to-Ambient		65	· C/VV	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	150			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.18		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.085		V _{GS} = 10V, I _D = 8.4A ④
1 103(011)				0.095	Ω	V _{GS} = 5.0V, I _D = 8.4A ④
V _{GS(th)}	Gate Threshold Voltage	1.0		2.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
g fs	Forward Transconductance	14			S	$V_{DS} = 50V, I_{D} = 8.4A$
1	Drain-to-Source Leakage Current			25		$V_{DS} = 150V, V_{GS} = 0V$
I _{DSS}	Diam-to-Source Leakage Current			250	μA	$V_{DS} = 120V, V_{GS} = 0V, T_{J} = 150$ °C
1	Gate-to-Source Forward Leakage			100	- ^	V _{GS} = 16V
I_{GSS}	Gate-to-Source Reverse Leakage			-100	nA	$V_{GS} = -16V$
Qg	Total Gate Charge			140		$I_D = 8.4A$
Q_{gs}	Gate-to-Source Charge			9.5	nC	$V_{DS} = 120V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			53		V_{GS} = 10V, See Fig. 6 and 13 \oplus
t _{d(on)}	Turn-On Delay Time		8.3			$V_{DD} = 75V$
t _r	Rise Time		20		ns	$I_D = 8.4A$
t _{d(off)}	Turn-Off Delay Time		110		113	$R_G = 6.2\Omega$, $V_{GS} = 10V$
t _f	Fall Time		53			$R_D = 8.9\Omega$, See Fig. 10 @
1-	Internal Drain Inductance		4.5 —		Between lead,	
L _D	Internal Drail inductance				-11	6mm (0.25in.)
L _S	Internal Source Inductance		7.5		hH	from package
-8	internal Source inductance		/ .5			and center of die contact
C _{iss}	Input Capacitance		1600			$V_{GS} = 0V$
Coss	Output Capacitance		290		pF	$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		150			f = 1.0MHz, See Fig. 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current			14⑤ A	MOSFET symbol		
	(Body Diode)		- 145		showing the		
I _{SM}	Pulsed Source Current						integral reverse
	(Body Diode) ①	<u></u> 56		p-n junction diode.			
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 8.4A$, $V_{GS} = 0V$ ④	
t _{rr}	Reverse Recovery Time		180	270	ns	$T_J = 25$ °C, $I_F = 8.4$ A	
Q _{rr}	Reverse RecoveryCharge		1130	1700	nC	di/dt = 100A/µs ④	
ton	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)					

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\begin{tabular}{ll} \hline @ Starting $T_J = 25^\circ$C, $L = 9.5mH$\\ $R_G = 25\Omega, I_{AS} = 8.4A. (See Figure 12) \\ \hline \end{tabular}$
- $\begin{tabular}{ll} \begin{tabular}{ll} \be$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- ⑤ Caculated continuous current based on maximum allowable junction temperature; for recommended current-handling of the package refer to Design Tip # 93-4.

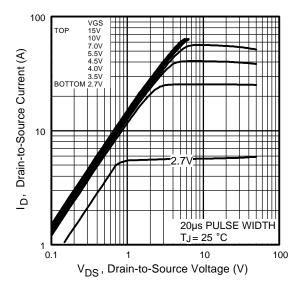


Fig 1. Typical Output Characteristics

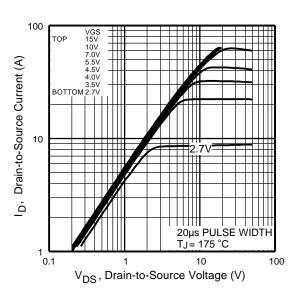


Fig 2. Typical Output Characteristics

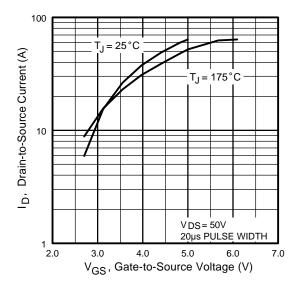


Fig 3. Typical Transfer Characteristics

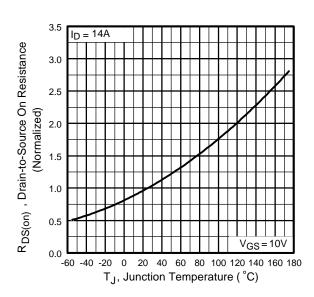


Fig 4. Normalized On-Resistance Vs. Temperature

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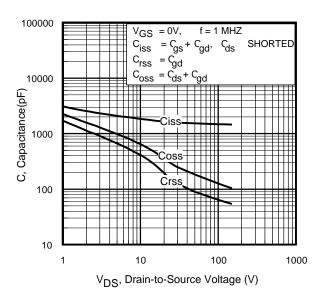


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

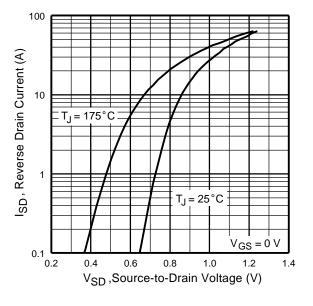


Fig 7. Typical Source-Drain Diode Forward Voltage

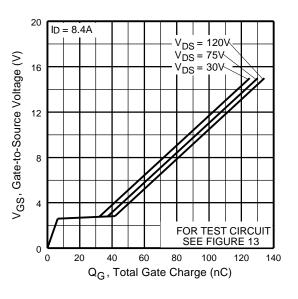


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

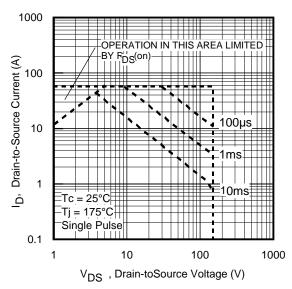


Fig 8. Maximum Safe Operating Area

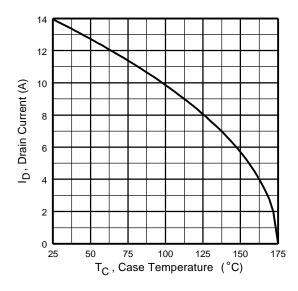


Fig 9. Maximum Drain Current Vs. Case Temperature

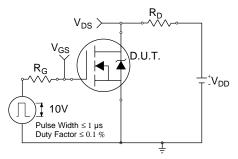


Fig 10a. Switching Time Test Circuit

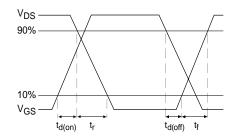


Fig 10b. Switching Time Waveforms

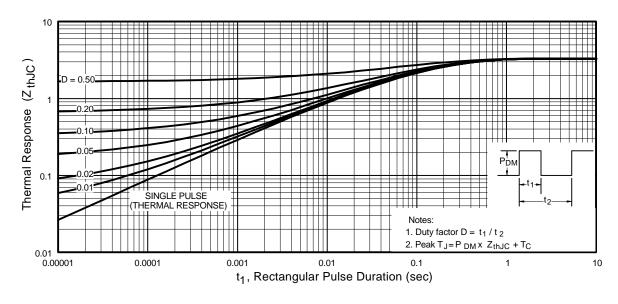


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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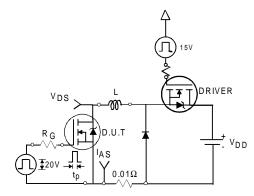


Fig 12a. Unclamped Inductive Test Circuit

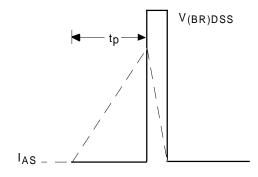


Fig 12b. Unclamped Inductive Waveforms

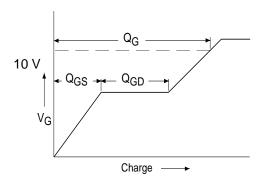


Fig 13a. Basic Gate Charge Waveform

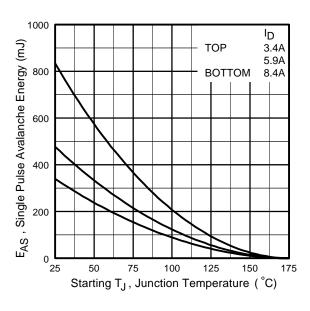


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

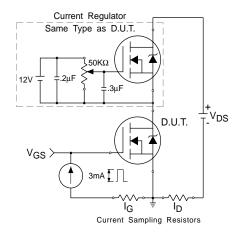
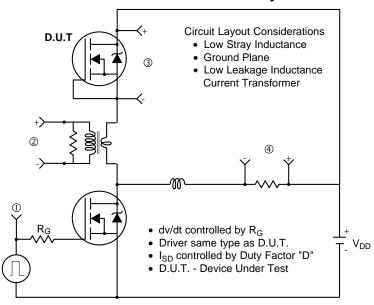


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



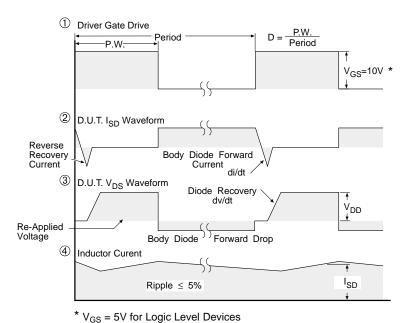
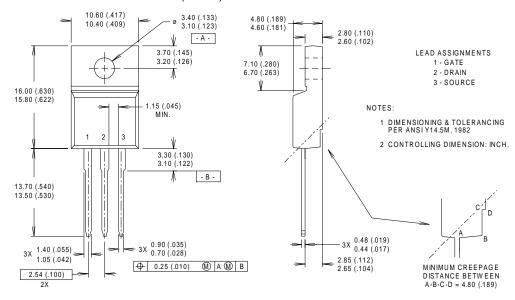


Fig 14. For N-Channel HEXFETS

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Package Outline TO-220 Fullpak Outline

Dimensions are shown in millimeters (inches)

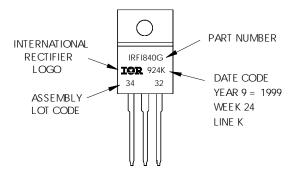


Part Marking Information TO-220 Fullpak

EXAMPLE: THIS IS AN IRF1840G

WITH ASSEMBLY LOT CODE 3432

ASSEMBLED ON WW 24 1999 IN THE ASSEMBLY LINE "K"



Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.



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